



PATENT  
1152-0263P

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant: Hideaki SAKAGUCHI Conf.: 4601  
Appl. No.: 09/624,014 Group: 2857  
Filed: July 21, 2000 Examiner: Mary C. BARAN  
For: TESTING DEVICE & TESTING METHOD FOR  
SEMICONDUCTOR INTEGRATED CIRCUITS

**COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

May 12, 2004

Sir:

The Examiner's statement of reasons for allowance appears to present an accurate summary of features not shown in the prior art of record. However, Applicant notes that it is the claims themselves that define the scope of the invention for which protection is sought.

Respectfully submitted,

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By 

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